



[54] DIGITAL CURRENT PROBE

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[57] CLAIM

[**] Term: 14 Years

The ornamental design for a digital current probe, as shown
and described.

[21] Appl. No.: 17,865

DESCRIPTION

[22] Filed: Jan. 24, 1994

[52] U.S. Cl. D10/79

[58] Field of Search D10/79; 324/73 R,
324/127, 129, 133, 149, 126, 128, 130,
158 F

FIG. 1 is a front perspective view of the digital current probe
of this invention;

FIG. 2 is a front plan view of FIG. 1;

FIG. 3 is a plan view of the rear of FIG. 1;

FIG. 4 is a plan view of FIG. 1 as seen from the right side
of FIG. 2;

FIG. 5 is a view of the left side of FIG. 2;

FIG. 6 is a top plan view of FIG. 2; and,

FIG. 7 is a bottom plan view of FIG. 2.

[56] References Cited

U.S. PATENT DOCUMENTS

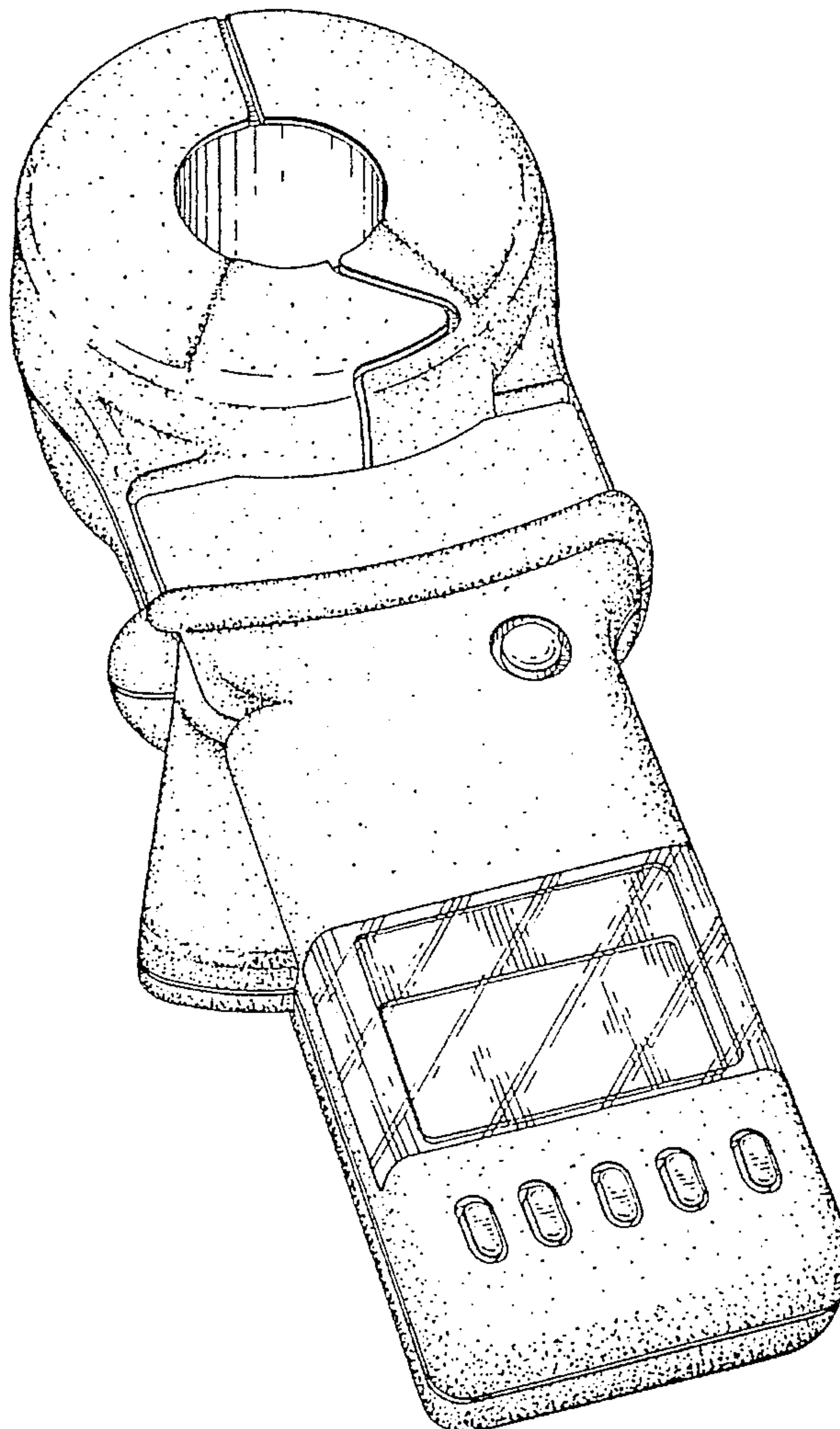
D. 332,574 1/1993 Chang D10/79 X
D. 345,704 4/1994 Shirai D10/79
4,283,677 8/1981 Niwa D10/79 X

OTHER PUBLICATIONS

I.E.N.; Clamp-on multimeter; Nov. 1978; pp. 5–9.

Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine D. Davis

1 Claim, 5 Drawing Sheets



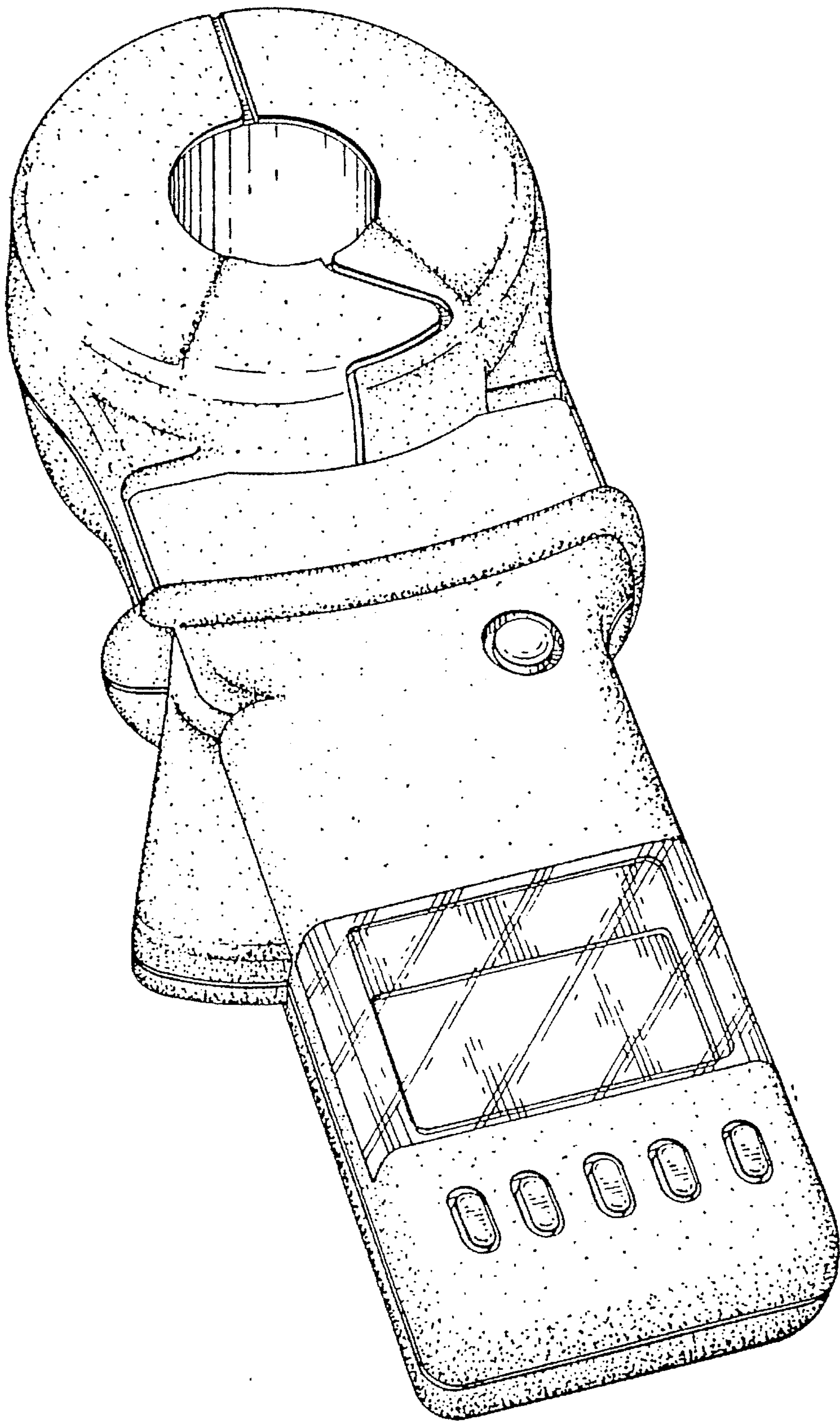


FIG. 1

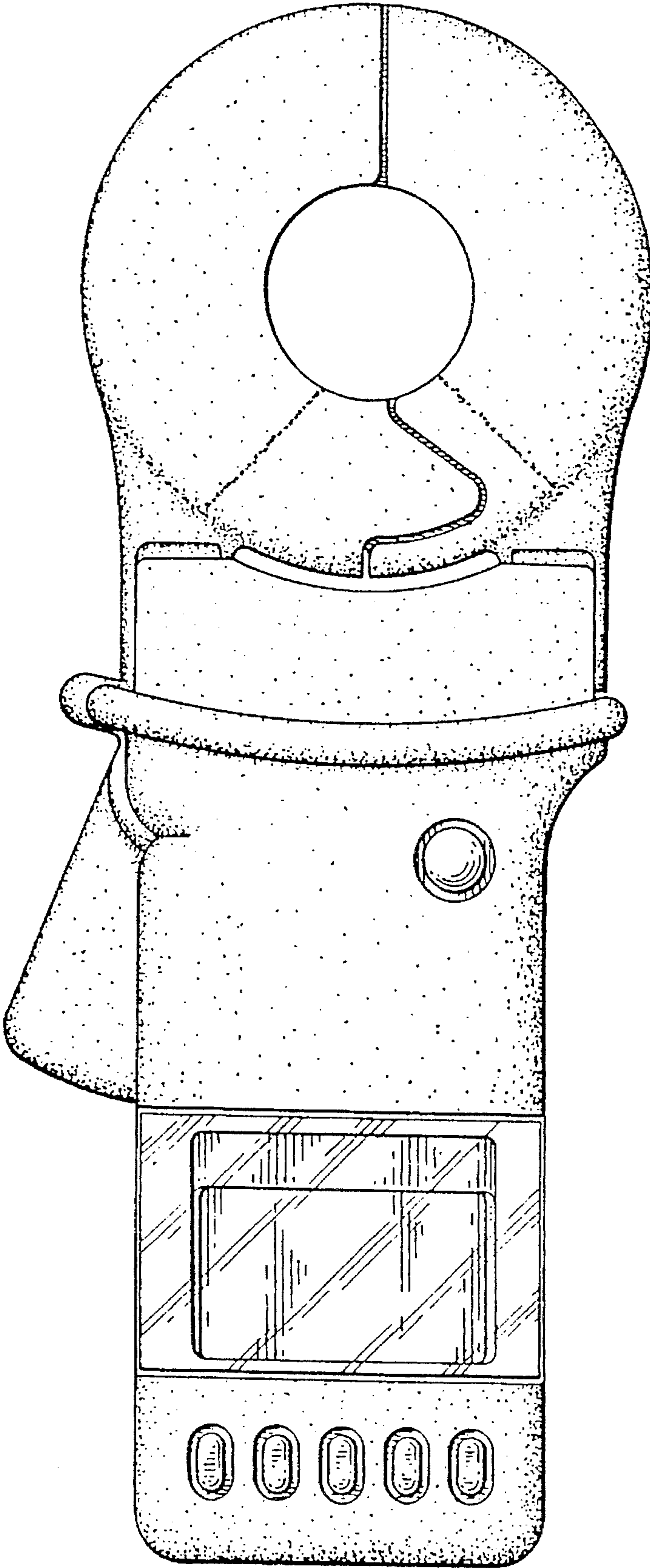


FIG. 2

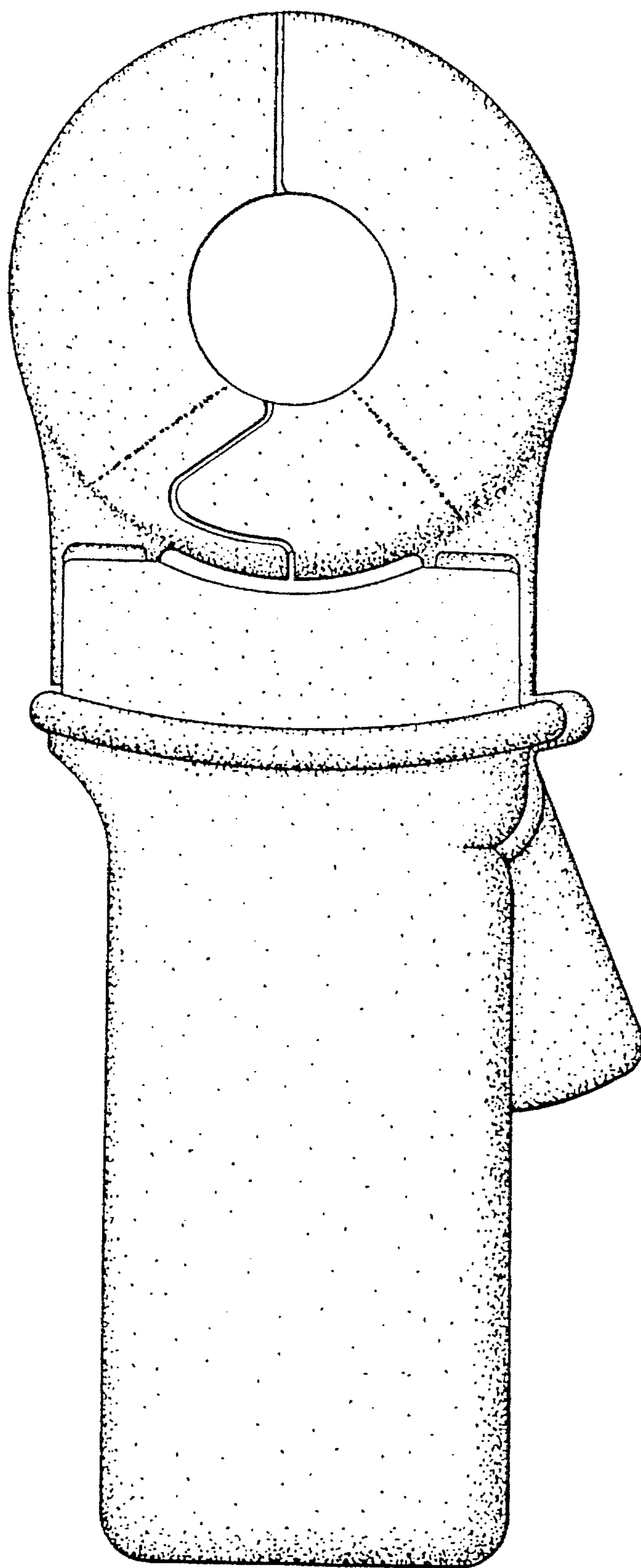


FIG. 3

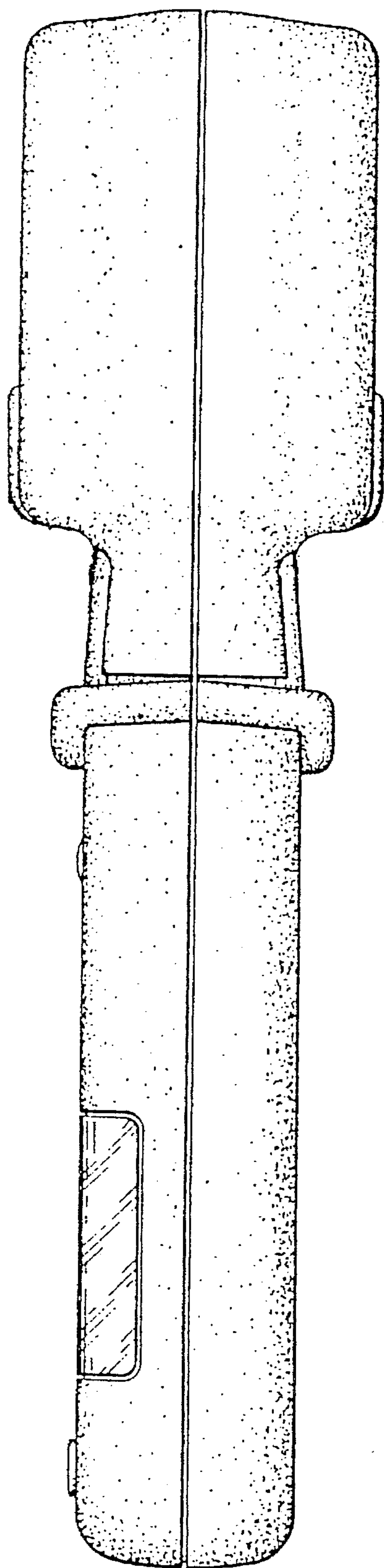


FIG. 4

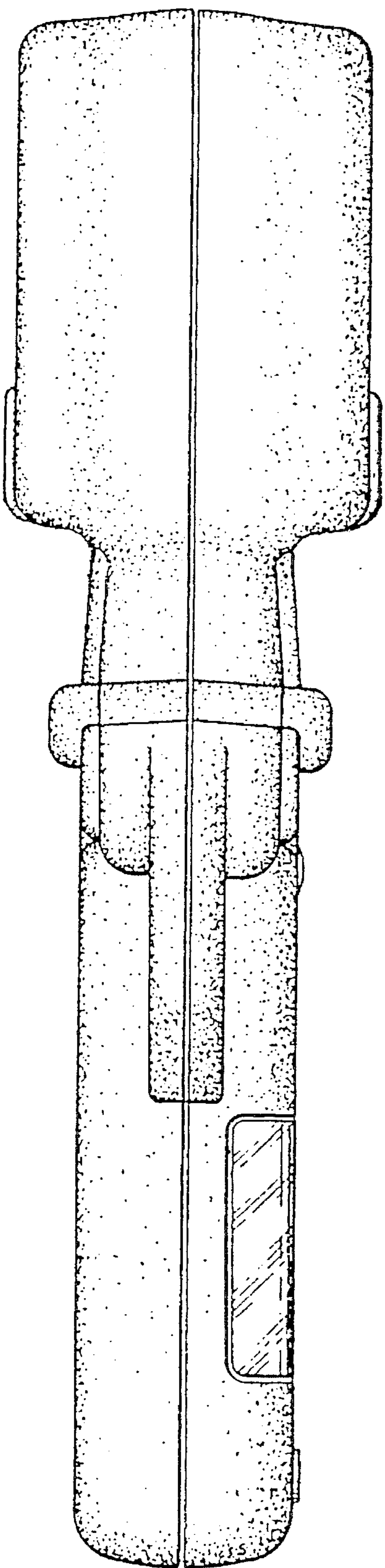


FIG. 5

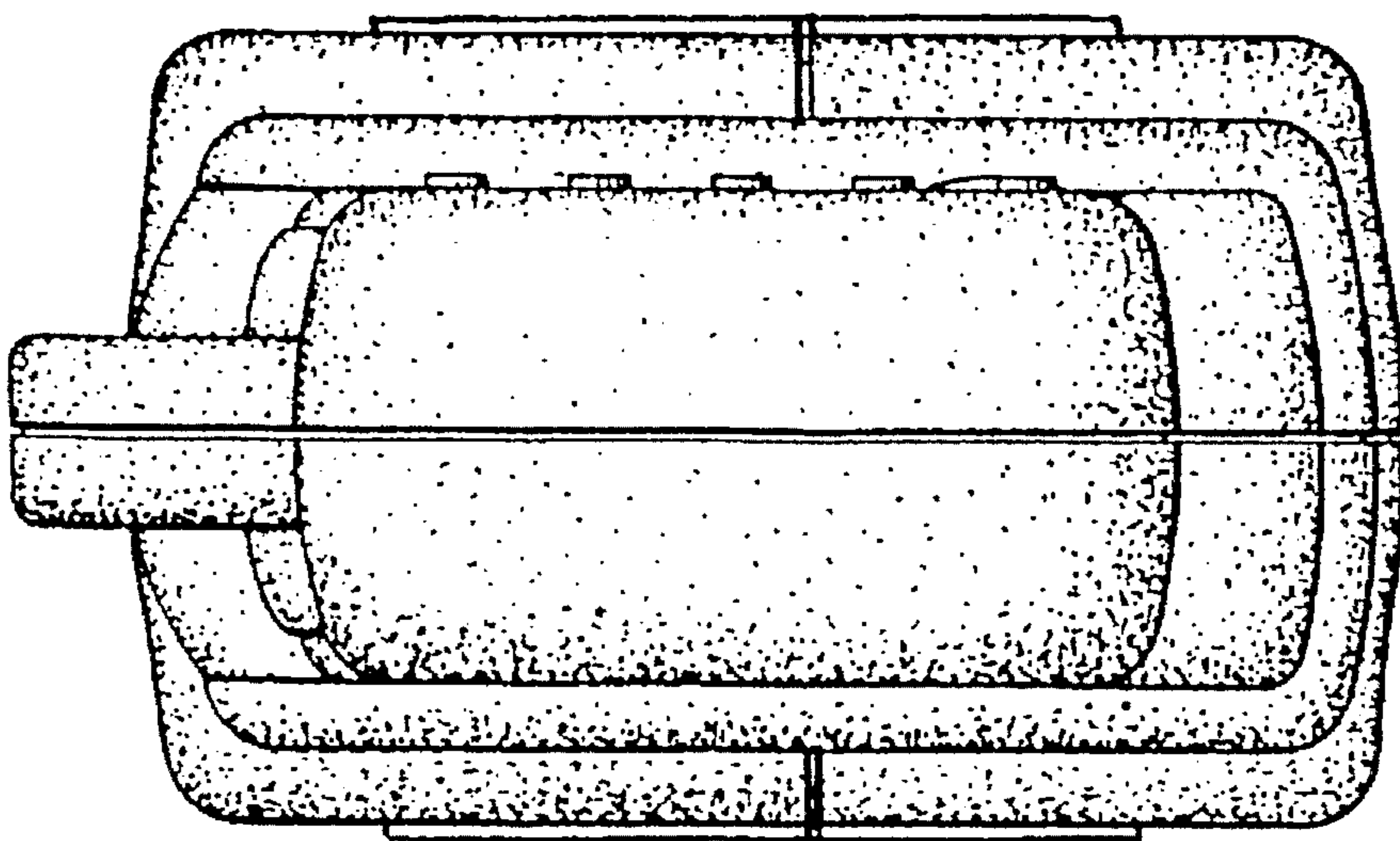


FIG. 6

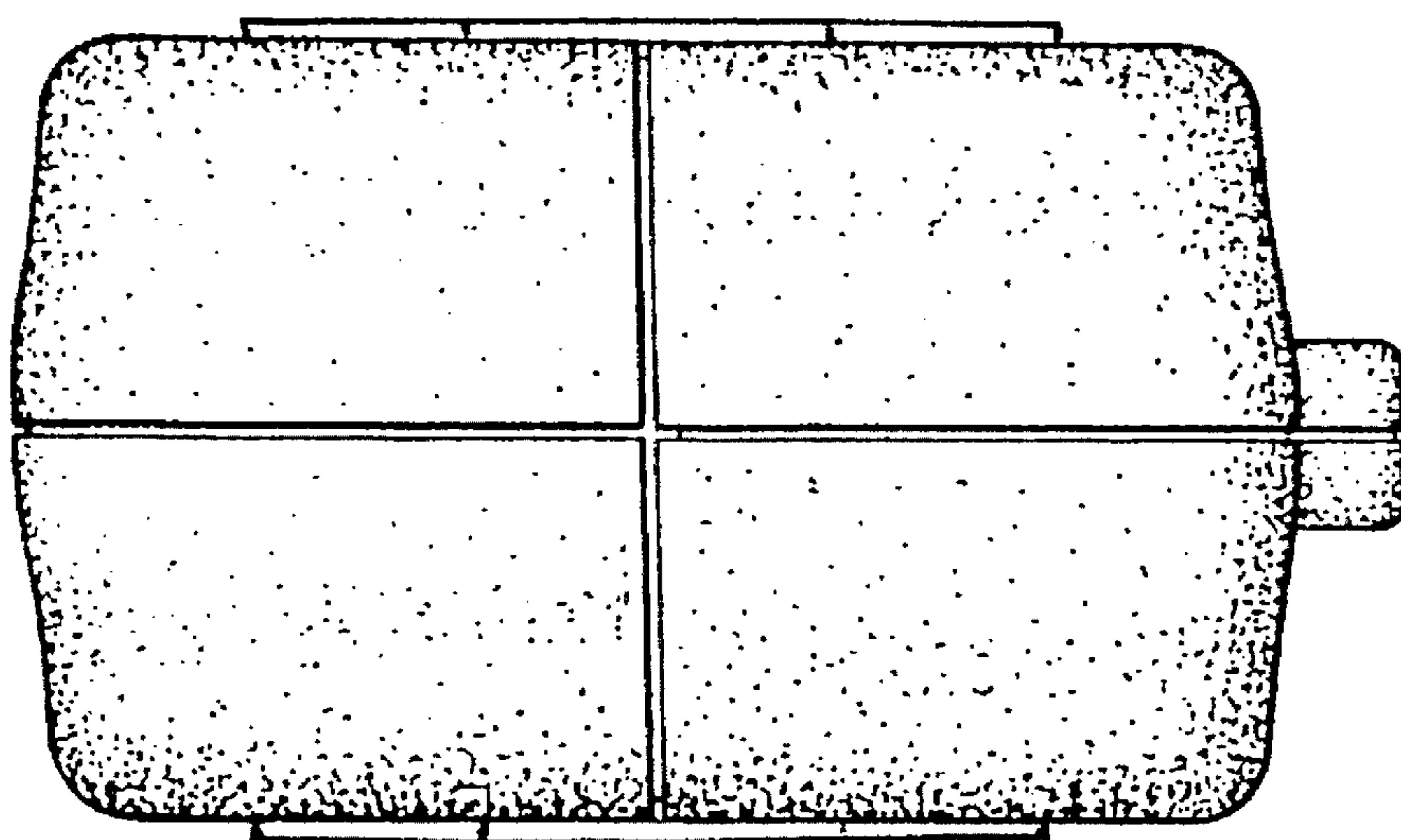


FIG. 7